



ORIENTAL
SEMICONDUCTOR

GreenMOS™

OSG60R2K8xF_Datasheet

Green
PRODUCT

RoHS
compliant

Enhancement Mode N-Channel Power MOSFET

Features

- ◆ Low $R_{DS(on)}$ & FOM
- ◆ Extremely low switching loss
- ◆ Excellent stability and uniformity
- ◆ Easy to drive

Applications

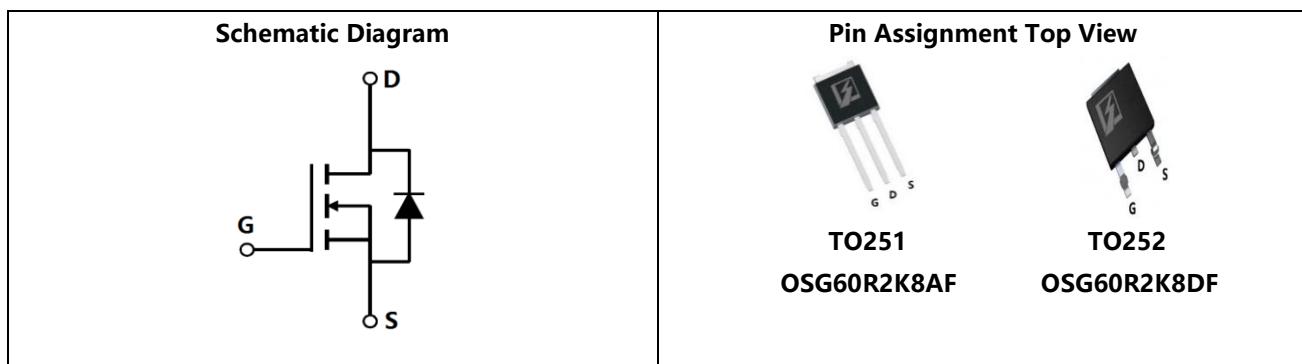
- ◆ Lighting
- ◆ Hard switching PWM
- ◆ Server power supply
- ◆ Charger

■ General Description

OSG60R2K8xF use advanced GreenMOS™ technology to provide low $R_{DS(ON)}$, low gate charge, fast switching and excellent avalanche characteristics. This device is suitable for active power factor correction and switching mode power supply applications.

◆ $V_{DS, min@Tjmax}$	650 V
◆ $I_D, pulse$	4.5 A
◆ $R_{DS(ON)}, \text{max } @ VGS=10 \text{ V}$	2.8 Ω
◆ Q_g	4.2 nC

■ Schematic and Package Information



■ Absolute Maximum Ratings at $T_j=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Value	Unit
Drain source voltage	V_{DS}	600	V
Gate source voltage	V_{GS}	± 30	V
Continuous drain current ¹⁾ , $T_C=25^\circ\text{C}$	I_D	1.5	A
Continuous drain current ¹⁾ , $T_C=100^\circ\text{C}$		0.95	
Pulsed drain current ²⁾ , $T_C=25^\circ\text{C}$	$I_{D, \text{pulse}}$	4.5	A
Power dissipation ³⁾ , $T_C=25^\circ\text{C}$	P_D	18.1	W
Single pulsed avalanche energy ⁵⁾	E_{AS}	10	mJ
MOSFET dv/dt ruggedness, $V_{DS}=0...480 \text{ V}$	dv/dt	50	V/ns
Reverse diode dv/dt, $V_{DS}=0...480 \text{ V}, I_{SD} \leq I_D$	dv/dt	15	V/ns
Operation and storage temperature	T_{stg}, T_j	-55 to 150	°C

■ Thermal Characteristics

Parameter	Symbol	Value	Unit
Thermal resistance, junction-case	$R_{\theta JC}$	6.9	°C/W
Thermal resistance, junction-ambient ⁴⁾	$R_{\theta JA}$	62	°C/W

■ Electrical Characteristics at $T_j=25$ °C unless otherwise specified

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Drain-source breakdown voltage	BV_{DSS}	600			V	$V_{GS}=0$ V, $I_D=250$ μA
		650	750			$V_{GS}=0$ V, $I_D=250$ μA, $T_j=150$ °C
Gate threshold voltage	$V_{GS(th)}$	2.0		4.0	V	$V_{DS}=V_{GS}$, $I_D=250$ μA
Drain-source on-state resistance	$R_{DS(ON)}$		2.5	2.8	Ω	$V_{GS}=10$ V, $I_D=0.75$ A
			5.6			$V_{GS}=10$ V, $I_D=0.75$ A, $T_j=150$ °C
Gate-source leakage current	I_{GSS}			100	nA	$V_{GS}=30$ V
				-100		$V_{GS}=-30$ V
Drain-source leakage current	I_{DSS}			1	μA	$V_{DS}=600$ V, $V_{GS}=0$ V

■ Dynamic Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Input capacitance	C_{iss}		111.9		pF	$V_{GS}=0$ V, $V_{DS}=50$ V, $f=1$ MHz
Output capacitance	C_{oss}		10.28		pF	
Reverse transfer capacitance	C_{rss}		0.86		pF	
Turn-on delay time	$t_{d(on)}$		23.9		ns	$V_{GS}=10$ V, $V_{DS}=400$ V, $R_G=25$ Ω, $I_D=0.8$ A
Rise time	t_r		8.1		ns	
Turn-off delay time	$t_{d(off)}$		52.7		ns	
Fall time	t_f		14.1		ns	

■ Gate Charge Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Total gate charge	Q_g		4.2		nC	$I_D=1\text{ A}$, $V_{DS}=400\text{ V}$, $V_{GS}=10\text{ V}$
Gate-source charge	Q_{gs}		1		nC	
Gate-drain charge	Q_{gd}		2.3		nC	
Gate plateau voltage	$V_{plateau}$		5.6		V	

■ Body Diode Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Diode forward current	I_S			1.5	A	$V_{GS} < V_{th}$
Pulsed source current	I_{SP}			4.5		
Diode forward voltage	V_{SD}			1.3	V	$I_S=1.5\text{ A}$, $V_{GS}=0\text{ V}$
Reverse recovery time	t_{rr}		81.9		ns	$I_S=0.8\text{ A}$, $di/dt=100\text{ A}/\mu\text{s}$
Reverse recovery charge	Q_{rr}		0.26		μC	
Peak reverse recovery current	I_{rrm}		6.5		A	

■ Note

- 1) Calculated continuous current based on maximum allowable junction temperature.
- 2) Repetitive rating; pulse width limited by max. junction temperature.
- 3) P_d is based on max. junction temperature, using junction-case thermal resistance.
- 4) The value of $R_{\theta JA}$ is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with $T_a=25\text{ }^{\circ}\text{C}$.
- 5) $V_{DD}=50\text{ V}$, $R_G=25\text{ }\Omega$, $L=22.5\text{ mH}$, starting $T_j=25\text{ }^{\circ}\text{C}$.

■ Electrical Characteristics Diagrams

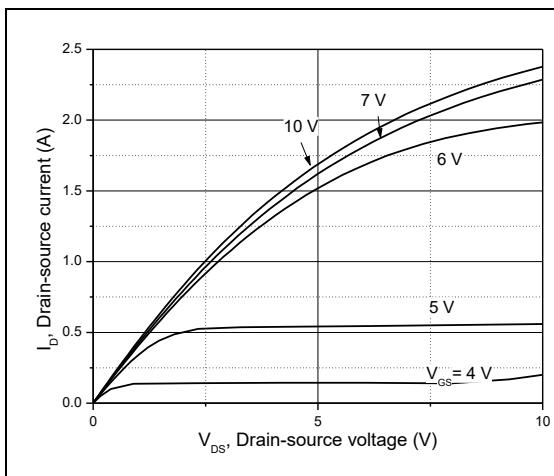


Figure 1, Typ. output characteristics

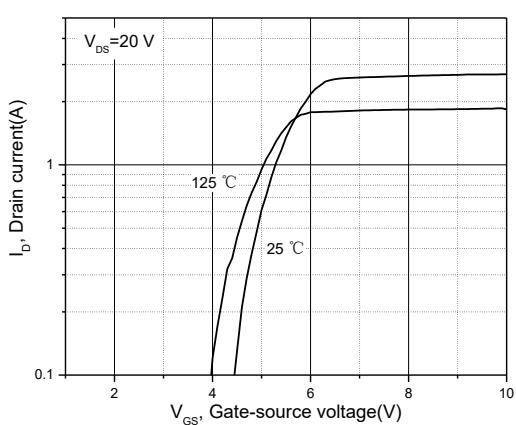


Figure 2, Typ. transfer characteristics

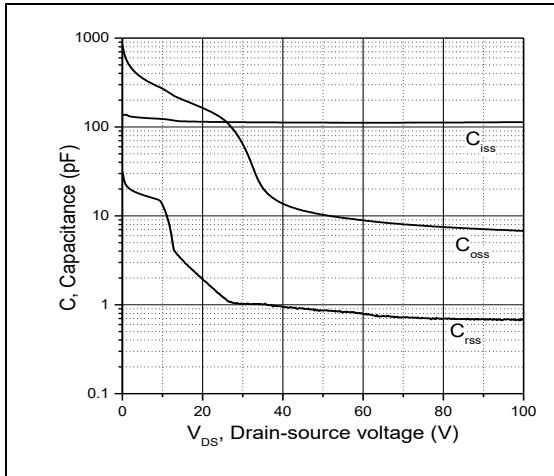


Figure 3, Typ. capacitances

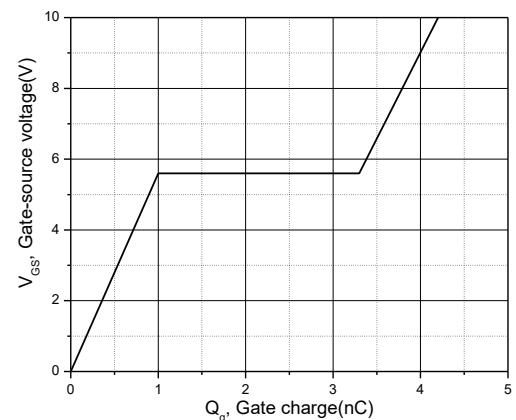


Figure 4, Typ. gate charge

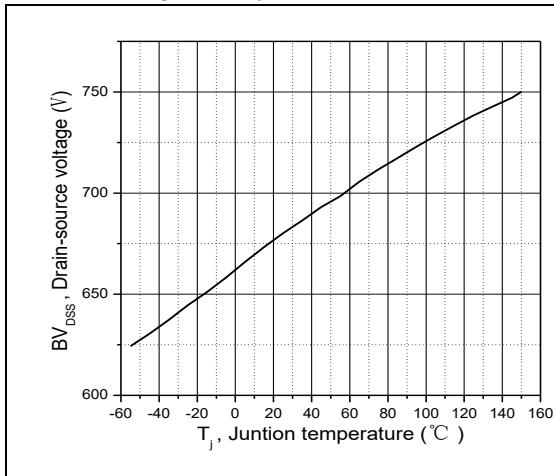


Figure 5, Drain-source breakdown voltage

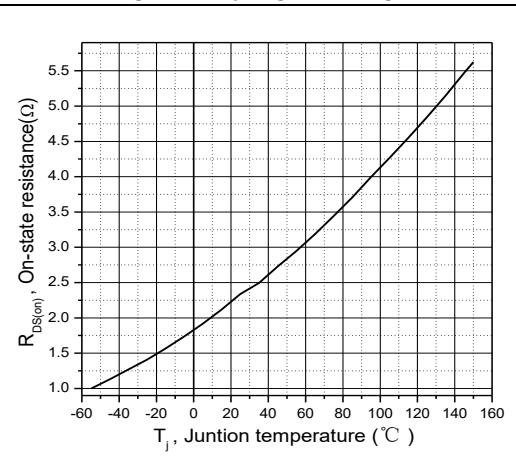


Figure 6, Drain-source on-state resistance

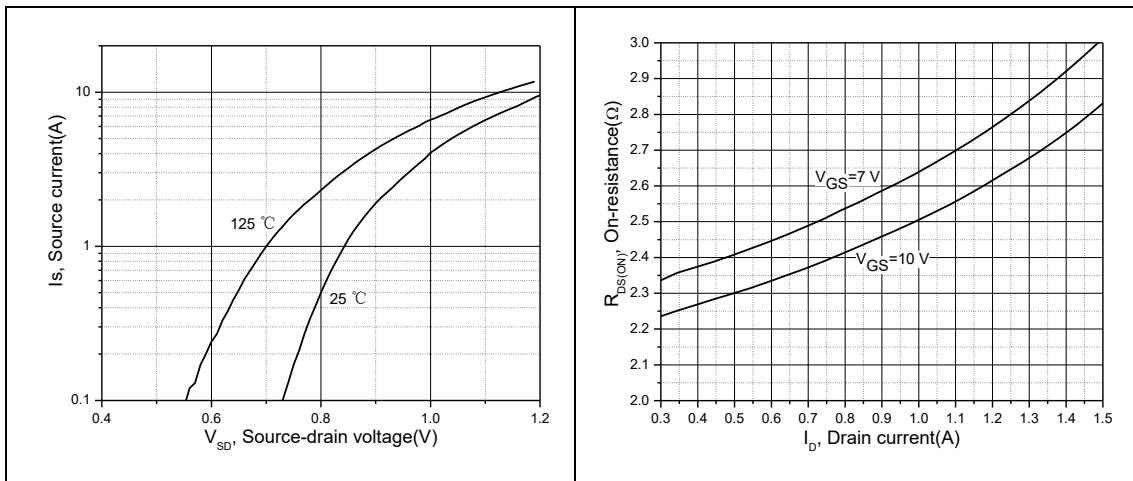


Figure 7, Forward characteristic of body diode

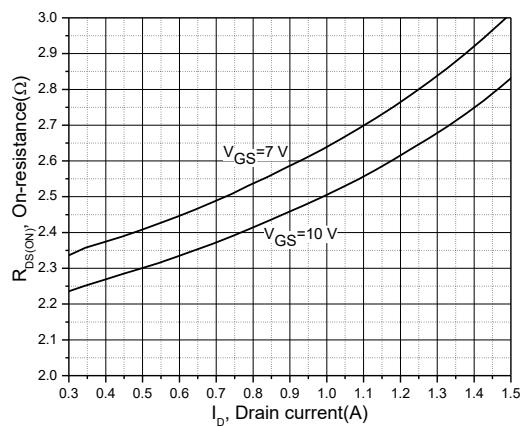


Figure 8, Drain-source on-state resistance

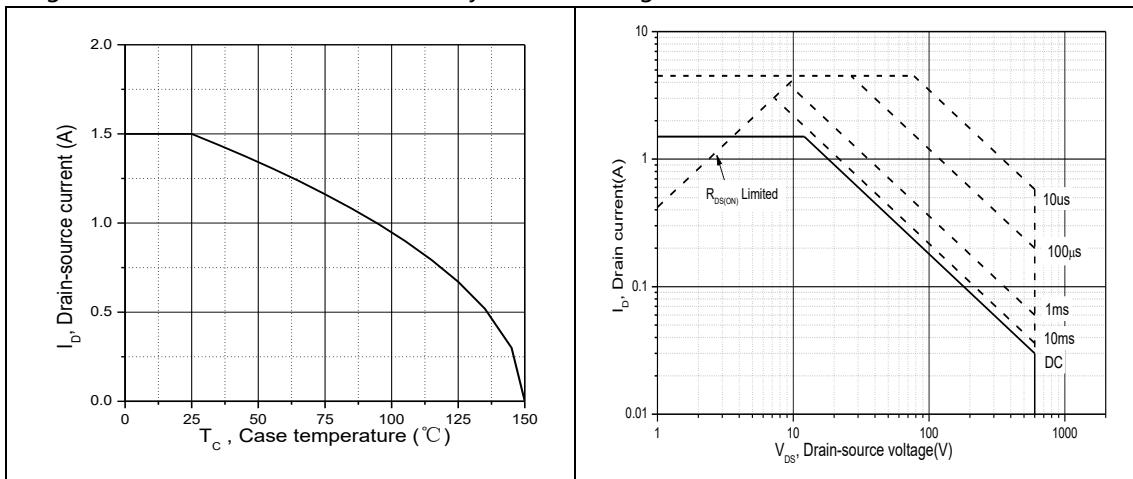
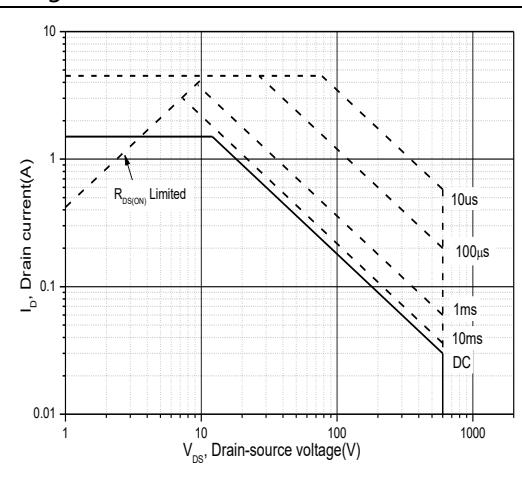


Figure 9, Drain current


 Figure 10, Safe operation area $T_c=25\text{ }^\circ\text{C}$

■ Test circuits and waveforms

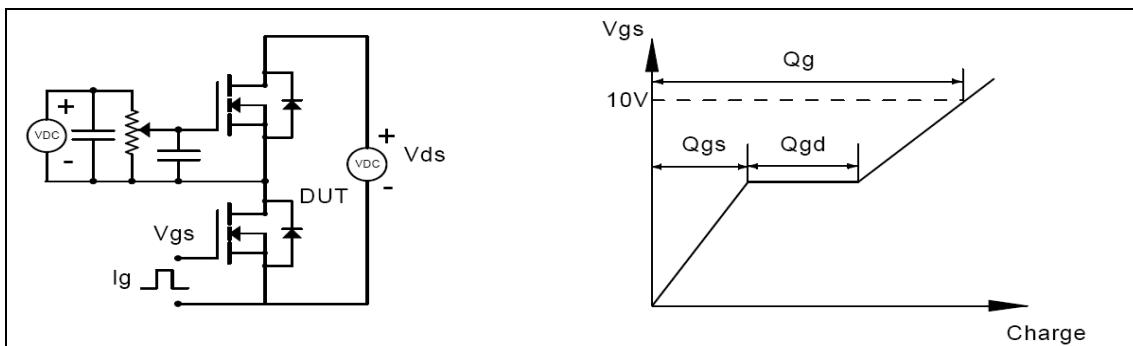


Figure 1, Gate charge test circuit & waveform

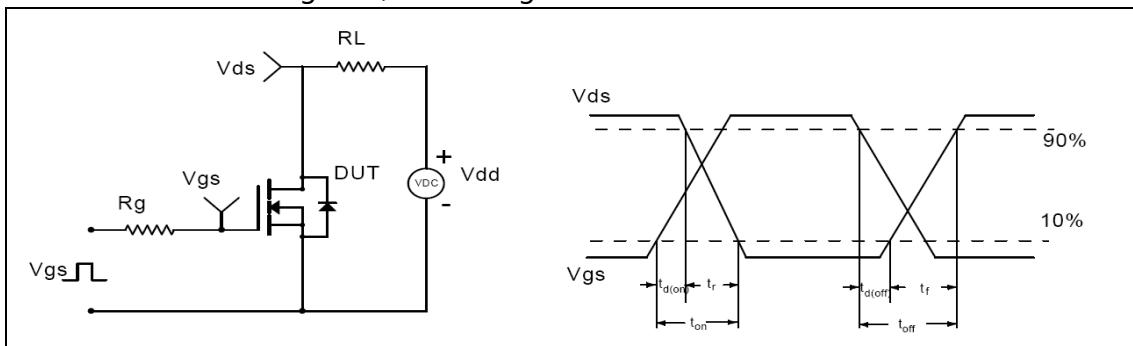


Figure 2, Switching time test circuit & waveforms

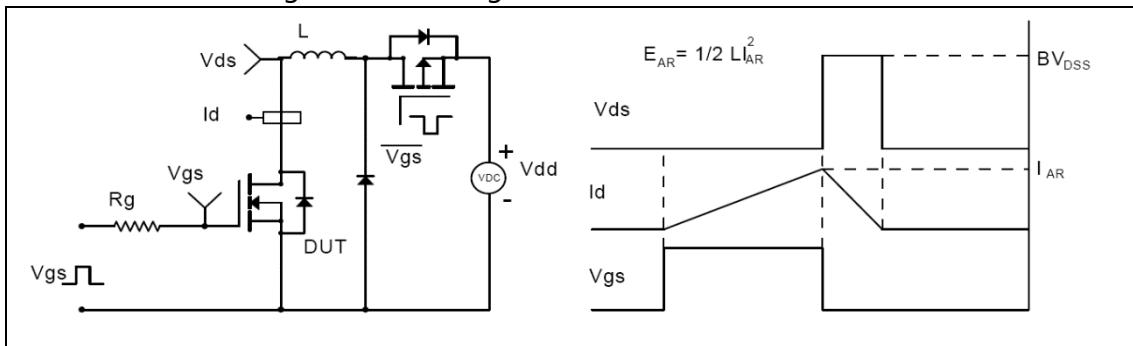


Figure 3, Unclamped inductive switching (UIS) test circuit & waveforms

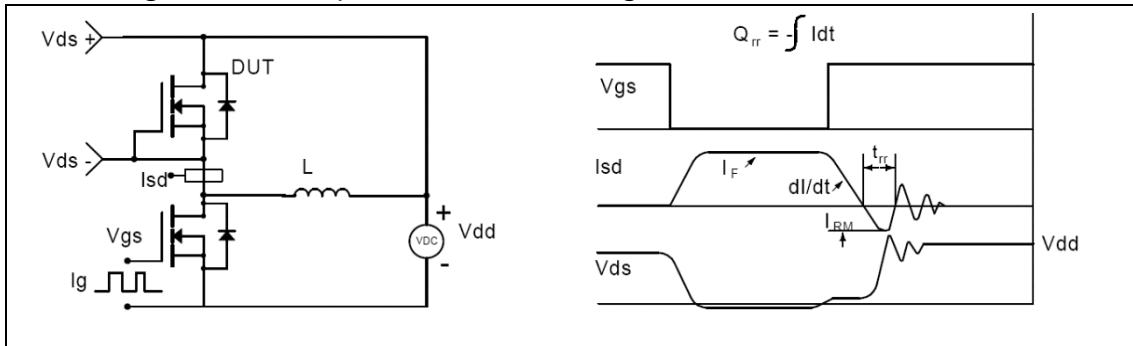
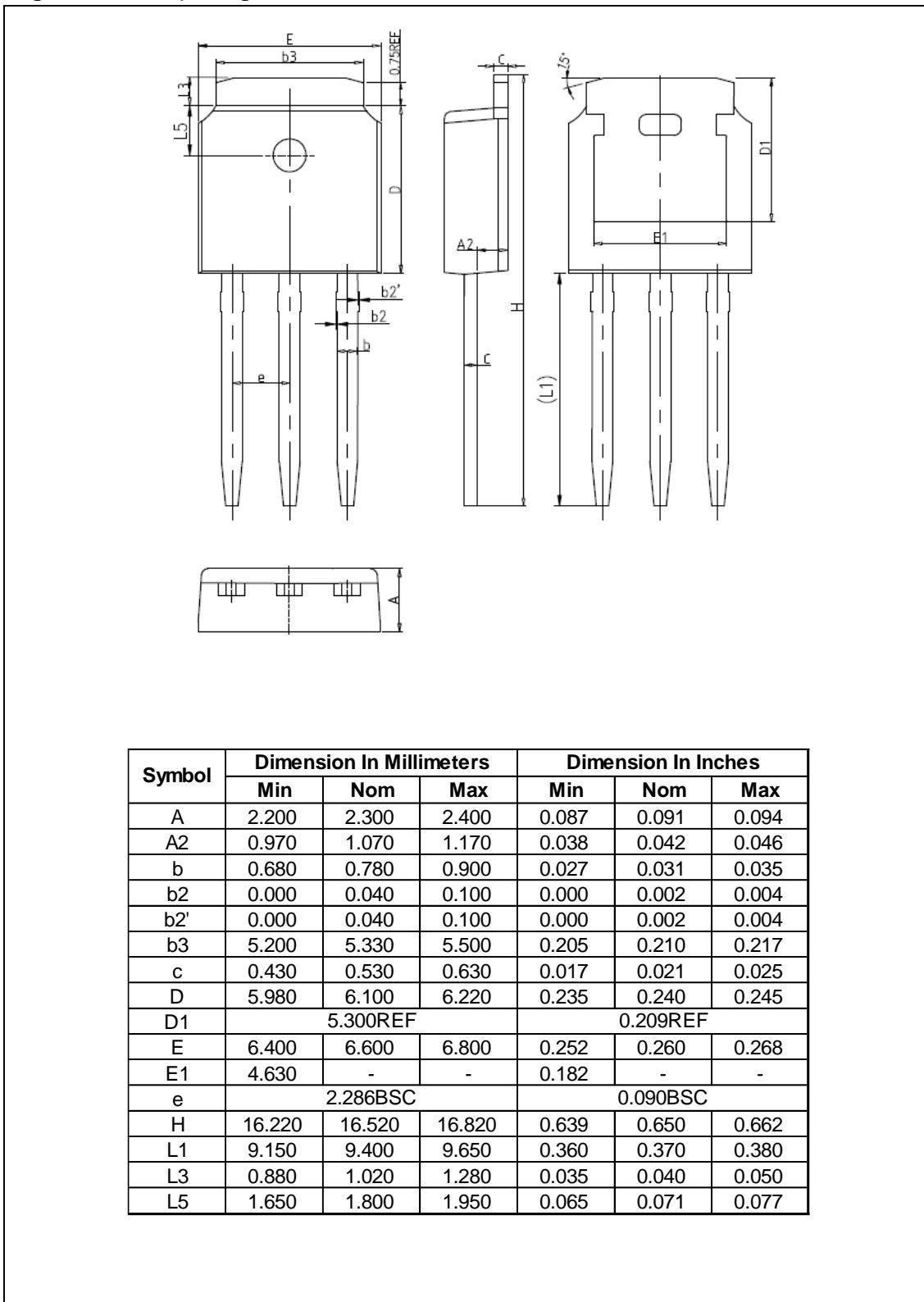


Figure 4, Diode reverse recovery test circuit & waveforms

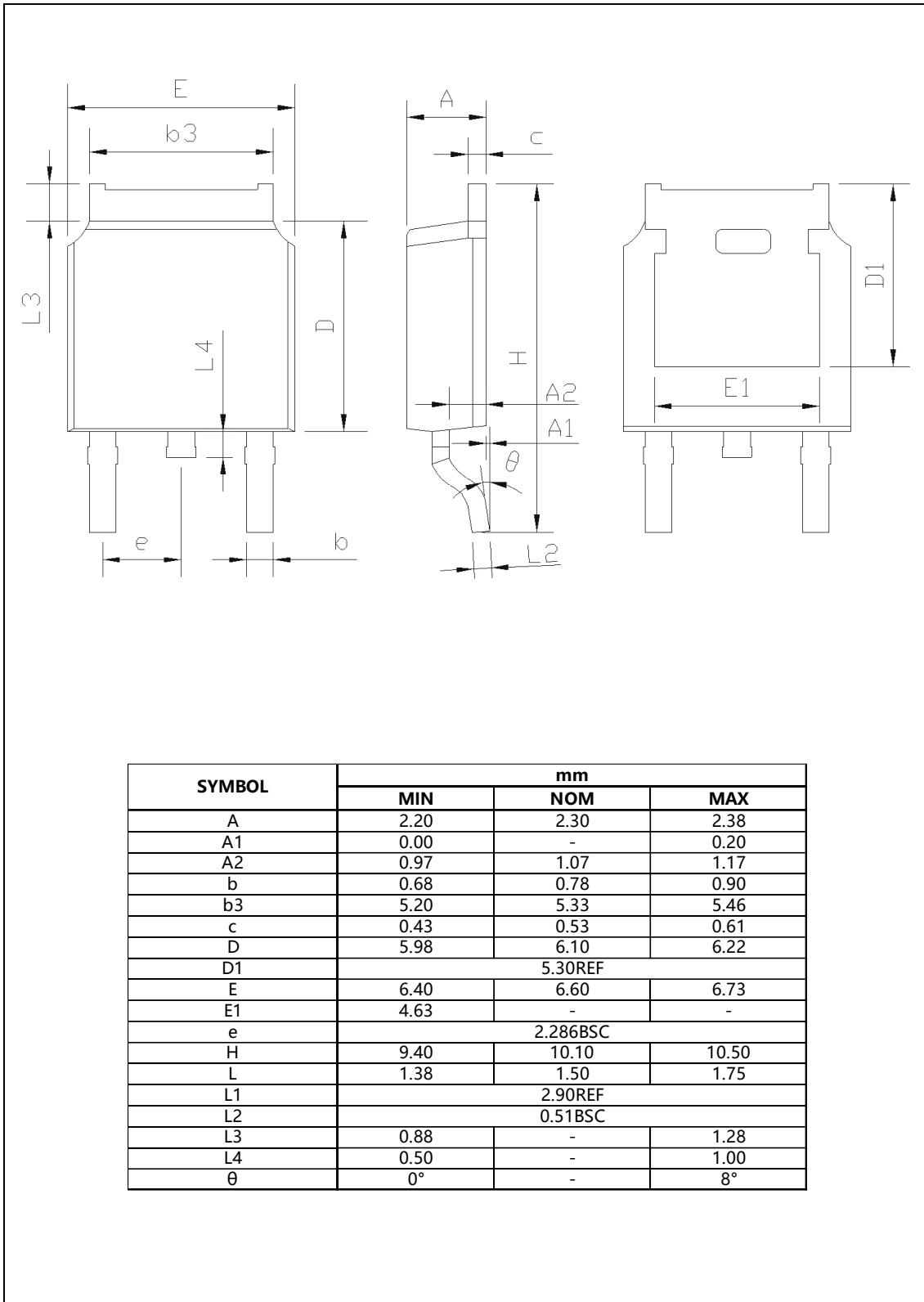
■ Package Information

Figure1, TO251 package outline dimension



■ Package Information

Figure2, TO252 package outline dimension



SYMBOL	mm		
	MIN	NOM	MAX
A	2.20	2.30	2.38
A1	0.00	-	0.20
A2	0.97	1.07	1.17
b	0.68	0.78	0.90
b3	5.20	5.33	5.46
c	0.43	0.53	0.61
D	5.98	6.10	6.22
D1	5.30REF		
E	6.40	6.60	6.73
E1	4.63	-	-
e	2.286BSC		
H	9.40	10.10	10.50
L	1.38	1.50	1.75
L1	2.90REF		
L2	0.51BSC		
L3	0.88	-	1.28
L4	0.50	-	1.00
θ	0°	-	8°

■ Ordering Information

Package	Units/Tube	Tubes/Inner Box	Units/Inner Box	Inner Box/Carton Box	Units/Carton Box
TO251	75	66	4950	6	29700

Package	Units/Tape	Tapes/Inner Box	Units/Inner Box	Inner Box/Carton Box	Units/Carton Box
TO252	2500	2	5000	5	25000

■ Product Information

Product	Package	Pb Free	RoHS	Halogen Free
OSG60R2K8AF	TO251	yes	yes	yes
OSG60R2K8DF	TO252	yes	yes	yes